

Search Notes

Application/Control No.

10/527,775

Examiner

Richard Chan

Applicant(s)/Patent under
Reexamination

VAN BEZOOIJEN ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	299	9/27/2006	RC
455	127.1	9/26/2006	RC
455	572	9/26/2006	RC
455	114.3	9/27/2006	RC
455	280	9/27/2006	RC
455	291	9/27/2006	RC
455	311	9/27/2006	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR